

C1808C102JBRACTU

Aliases (C1808C102JBRAC7800)

SMD Comm X7R HV, Ceramic, 1,000 pF, 5%, 630 VDC, X7R, SMD, MLCC, High Voltage, Temperature Stable, 1808, 2.9 mm



General Information	
Series	SMD Comm X7R HV
Style	SMD Chip
Description	SMD, MLCC, High Voltage, Temperature Stable
Features	High Voltage
RoHS	Yes
Termination	Tin
Marking	No
AEC-Q200	No
Typical Component Weight	100 mg
Shelf Life	78 Weeks
MSL	1

Dimensions	
Chip Size	1808
L	4.7mm +/-0.5mm
W	2mm +/-0.2mm
Т	1.6mm +/-0.15mm
S	2.9mm MIN
В	0.6mm +/-0.35mm

W	2mm +/-0.2mm	Tolerance	5%
Т	1.6mm +/-0.15mm	Voltage DC	630 VDC
S	2.9mm MIN	Dielectric Withstanding Voltage	945 VDC
В	0.6mm +/-0.35mm	Temperature Range	-55/+125°C
		Temp. Coefficient	X7R
Packaging Specifications		Capacitance Change with	15%, 1kHz 1.0Vrms
Packaging	T&R, 180mm, Plastic Tape	Reference to +25°C and 0 VDC Applied (TCC)	,
Packaging Quantity	1000	Dissipation Factor	2.5%1kHz1.0Vrms
		Dissipation ractor	2.570 TRI IZ 1.0 VIIII3
		Aging Rate	3% Loss/Decade Hour: Referee

Specifications

Capacitance

Measurement Condition	1 kHz 1.0Vrms
Tolerance	5%
Voltage DC	630 VDC
Dielectric Withstanding Voltage	945 VDC
Temperature Range	-55/+125°C
Temp. Coefficient	X7R
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	15%, 1kHz 1.0Vrms
Dissipation Factor	2.5%1kHz1.0Vrms
Aging Rate	3% Loss/Decade Hour: Referee Time is 1000 Hours
Insulation Resistance	100 GOhms

1,000 pF

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